

AO3162-VB Datasheet

Power MOSFET

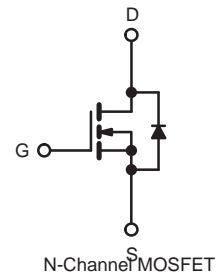
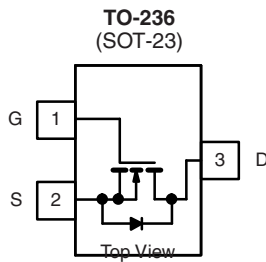
| PRODUCT SUMMARY | |
|---------------------------|----------------------------|
| V_{DS} (V) | 650 |
| $R_{DS(on)}$ (Ω) | $V_{GS} = 10\text{ V}$ 8 |
| Q_g (Max.) (nC) | 18 |
| Q_{gs} (nC) | 3.0 |
| Q_{gd} (nC) | 8.9 |
| Configuration | Single |

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Available in Tape and Reel
- Fast Switching
- Ease of Paralleling
- Compliant to RoHS Directive 2002/95/EC



Available
RoHS*
COMPLIANT
HALOGEN
FREE
Available



| ABSOLUTE MAXIMUM RATINGS $T_C = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | |
|--|------------------|-----------------------------------|---------------------|---|
| PARAMETER | SYMBOL | LIMIT | UNIT | |
| Drain-Source Voltage | V_{DS} | 650 | V | |
| Gate-Source Voltage | V_{GS} | ± 20 | | |
| Continuous Drain Current | V_{GS} at 10 V | $T_C = 25\text{ }^\circ\text{C}$ | 1.0 | A |
| | | $T_C = 100\text{ }^\circ\text{C}$ | 0.7 | |
| Pulsed Drain Current ^a | I_{DM} | 2.0 | W/ $^\circ\text{C}$ | |
| Linear Derating Factor | | 0.33 | | |
| Linear Derating Factor (PCB Mount) ^e | | 0.020 | | |
| Single Pulse Avalanche Energy ^b | E_{AS} | 74 | mJ | |
| Repetitive Avalanche Current ^a | I_{AR} | 2.0 | A | |
| Repetitive Avalanche Energy ^a | E_{AR} | 4.2 | mJ | |
| Maximum Power Dissipation | P_D | $T_C = 25\text{ }^\circ\text{C}$ | 42 | W |
| Maximum Power Dissipation (PCB Mount) ^e | | $T_A = 25\text{ }^\circ\text{C}$ | 2.5 | |
| Peak Diode Recovery dV/dt^c | dV/dt | 3.0 | V/ns | |
| Operating Junction and Storage Temperature Range | T_J, T_{stg} | - 55 to + 150 | $^\circ\text{C}$ | |
| Soldering Recommendations (Peak Temperature) | for 10 s | 260 ^d | | |

Notes

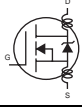

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 50\text{ V}$, starting $T_J = 25\text{ }^\circ\text{C}$, $L = 37\text{ mH}$, $R_g = 25\text{ }\Omega$, $I_{AS} = 2.0\text{ A}$ (see fig. 12).
- $I_{SD} \leq 2.0\text{ A}$, $dI/dt \leq 40\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DS}$, $T_J \leq 150\text{ }^\circ\text{C}$.
- 1.6 mm from case.
- When mounted on 1" square PCB (FR-4 or G-10 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply

| THERMAL RESISTANCE RATINGS | | | | | | |
|--|------------|------|------|------|------|--|
| PARAMETER | SYMBOL | MIN. | TYP. | MAX. | UNIT | |
| Maximum Junction-to-Ambient | R_{thJA} | - | - | 110 | °C/W | |
| Maximum Junction-to-Ambient (PCB Mount) ^a | R_{thJA} | - | - | 50 | | |
| Maximum Junction-to-Case (Drain) | R_{thJC} | - | - | 3.0 | | |

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

| SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted | | | | | | | |
|--|---------------------|--|--|------|------|-----------|---------------|
| PARAMETER | SYMBOL | TEST CONDITIONS | | MIN. | TYP. | MAX. | UNIT |
| Static | | | | | | | |
| Drain-Source Breakdown Voltage | V_{DS} | $V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$ | | 650 | - | - | V |
| V_{DS} Temperature Coefficient | $\Delta V_{DS}/T_J$ | Reference to $25\text{ }^\circ\text{C}$, $I_D = 1\text{ mA}$ | | - | 0.88 | - | V/°C |
| Gate-Source Threshold Voltage | $V_{GS(th)}$ | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ | | 2.0 | - | 4.0 | V |
| Gate-Source Leakage | I_{GSS} | $V_{GS} = \pm 20\text{ V}$ | | - | - | ± 100 | nA |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS} = 600\text{ V}, V_{GS} = 0\text{ V}$ | | - | - | 100 | μA |
| | | $V_{DS} = 480\text{ V}, V_{GS} = 0\text{ V}, T_J = 125\text{ }^\circ\text{C}$ | | - | - | 500 | |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $V_{GS} = 10\text{ V}$ | $I_D = 1.0\text{ A}^b$ | - | 8 | - | Ω |
| Forward Transconductance | g_{fs} | $V_{DS} = 50\text{ V}, I_D = 1.0\text{ A}$ | | 1.4 | - | - | S |
| Dynamic | | | | | | | |
| Input Capacitance | C_{iss} | $V_{GS} = 0\text{ V}, V_{DS} = -25\text{ V}, f = 1.0\text{ MHz}$, see fig. 5 | | - | 350 | - | pF |
| Output Capacitance | C_{oss} | | | - | 48 | - | |
| Reverse Transfer Capacitance | C_{rss} | | | - | 8.6 | - | |
| Total Gate Charge | Q_g | $V_{GS} = 10\text{ V}$ | $I_D = 1.0\text{ A}, V_{DS} = 360\text{ V}$, see fig. 6 and 13 ^b | - | - | 18 | nC |
| Gate-Source Charge | Q_{gs} | | | - | - | 3.0 | |
| Gate-Drain Charge | Q_{gd} | | | - | - | 8.9 | |
| Turn-On Delay Time | $t_{d(on)}$ | $V_{DD} = 300\text{ V}, I_D = 1.0\text{ A}, R_g = 18\text{ }\Omega, R_D = 135\text{ }\Omega$, see fig. 10 ^b | | - | 10 | - | ns |
| Rise Time | t_r | | | - | 23 | - | |
| Turn-Off Delay Time | $t_{d(off)}$ | | | - | 30 | - | |
| Fall Time | t_f | | | - | 25 | - | |
| Internal Drain Inductance | L_D | Between lead, 6 mm (0.25") from package and center of die contact  | | - | 4.5 | - | nH |
| Internal Source Inductance | L_S | | | - | 7.5 | - | |
| Drain-Source Body Diode Characteristics | | | | | | | |
| Continuous Source-Drain Diode Current | I_S | MOSFET symbol showing the integral reverse p - n junction diode  | | - | - | 2.0 | A |
| Pulsed Diode Forward Current ^a | I_{SM} | | | - | - | 8.0 | |
| Body Diode Voltage | V_{SD} | $T_J = 25\text{ }^\circ\text{C}, I_S = 2.0\text{ A}, V_{GS} = 0\text{ V}^b$ | | - | - | 1.6 | V |
| Body Diode Reverse Recovery Time | t_{rr} | $T_J = 25\text{ }^\circ\text{C}, I_F = 2.0\text{ A}, dI/dt = 100\text{ A}/\mu\text{s}^b$ | | - | 290 | 580 | ns |
| Body Diode Reverse Recovery Charge | Q_{rr} | | | - | 0.67 | 1.3 | μC |
| Forward Turn-On Time | t_{on} | Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D) | | | | | |

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
 b. Pulse width $\leq 300\text{ }\mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

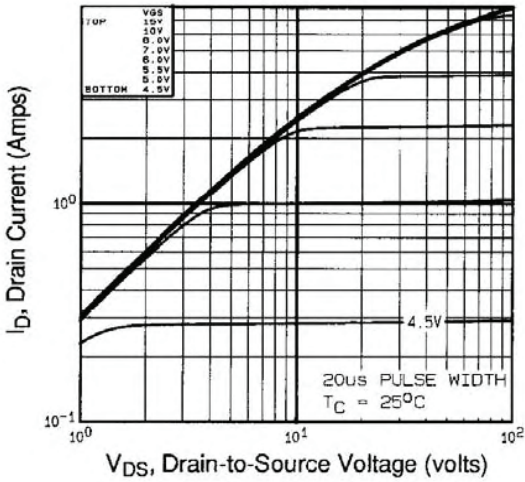


Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$

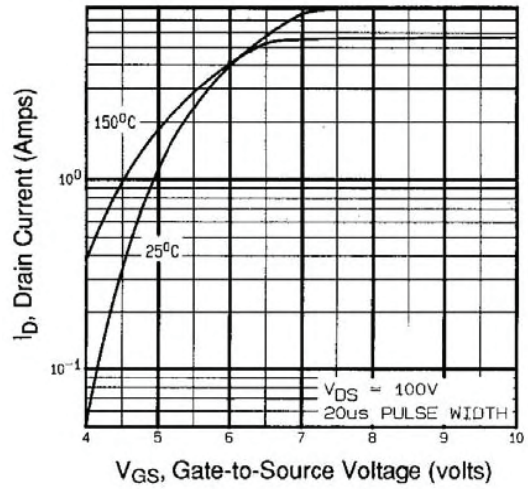


Fig. 3 - Typical Transfer Characteristics

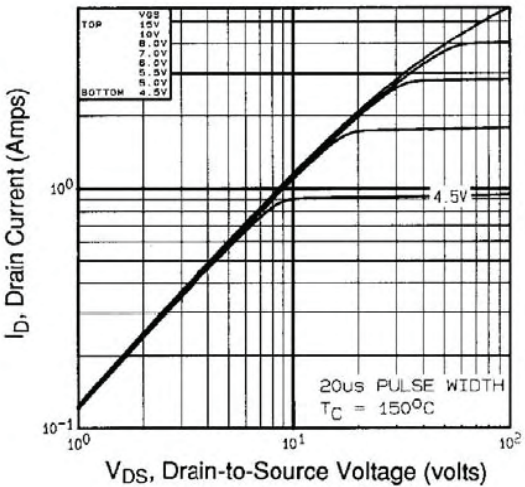


Fig. 2 - Typical Output Characteristics, $T_C = 150\text{ }^\circ\text{C}$

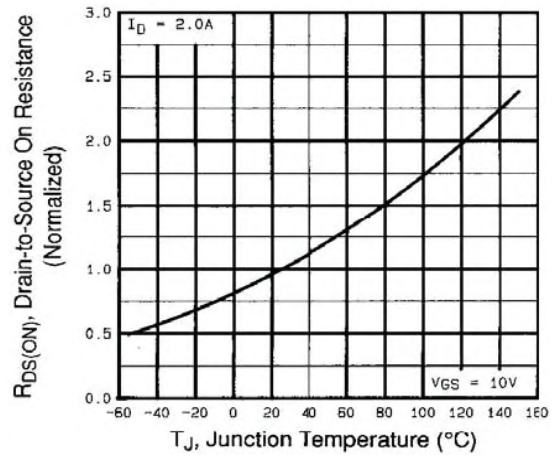


Fig. 4 - Normalized On-Resistance vs. Temperature

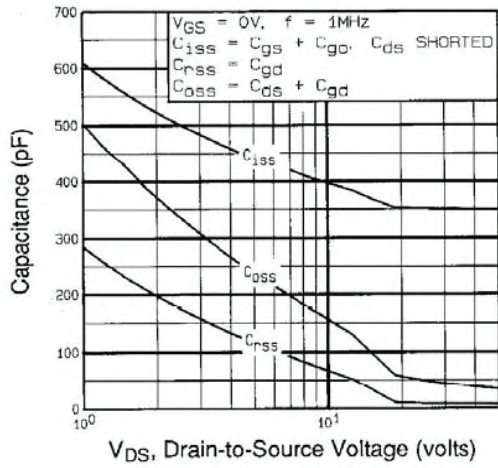


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

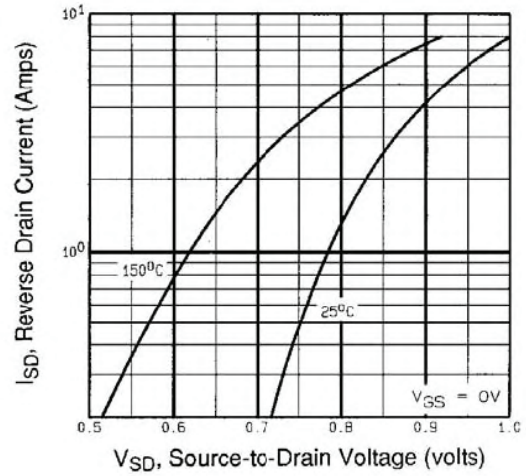


Fig. 7 - Typical Source-Drain Diode Forward Voltage

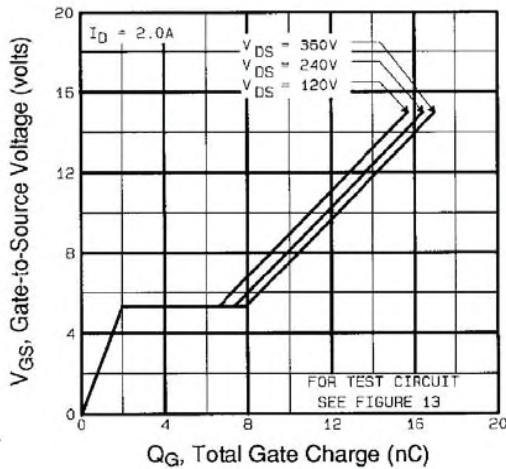


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

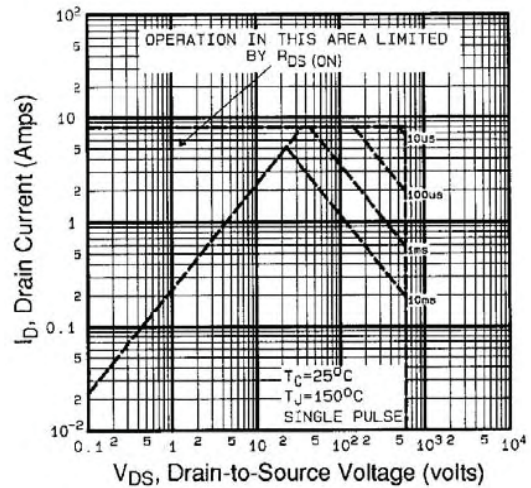


Fig. 8 - Maximum Safe Operating Area

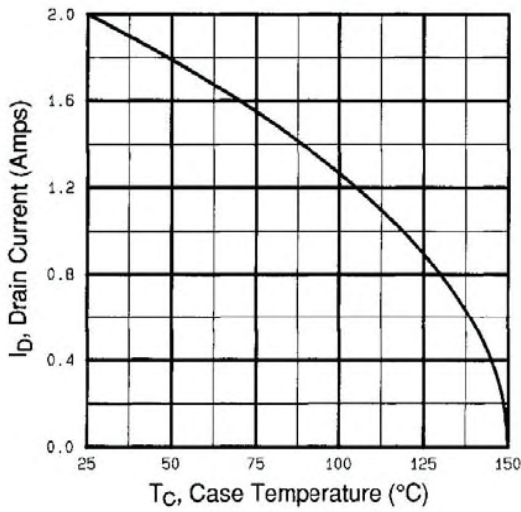


Fig. 9 - Maximum Drain Current vs. Case Temperature

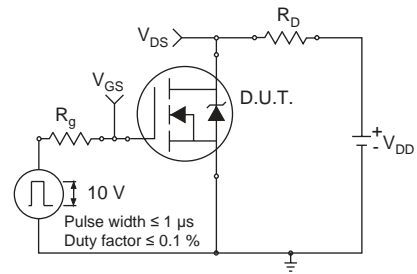


Fig. 10a - Switching Time Test Circuit

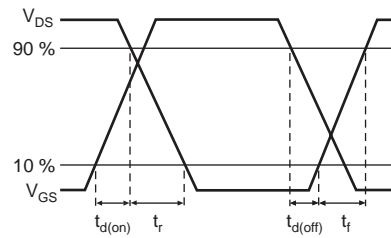


Fig. 10b - Switching Time Waveforms

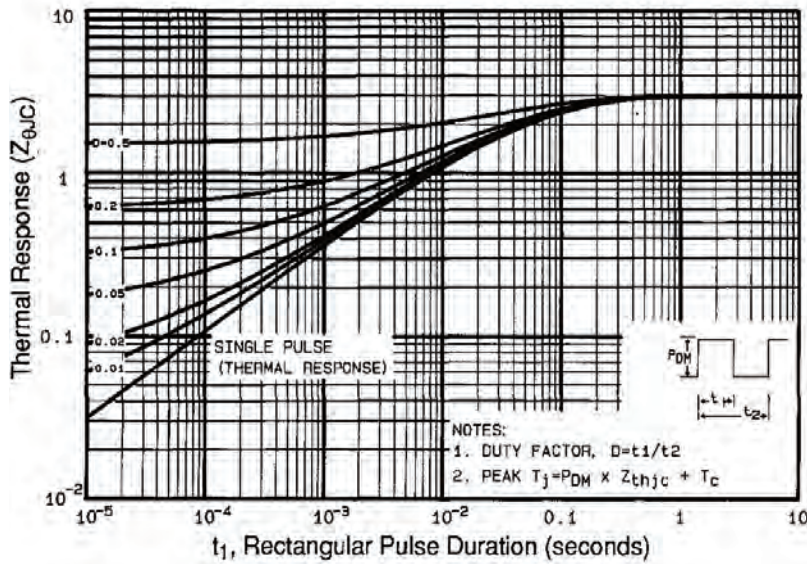


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

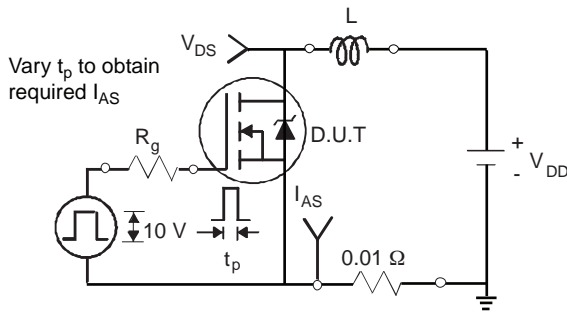


Fig. 12a - Unclamped Inductive Test Circuit

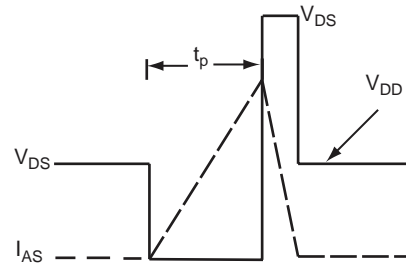


Fig. 12b - Unclamped Inductive Waveforms

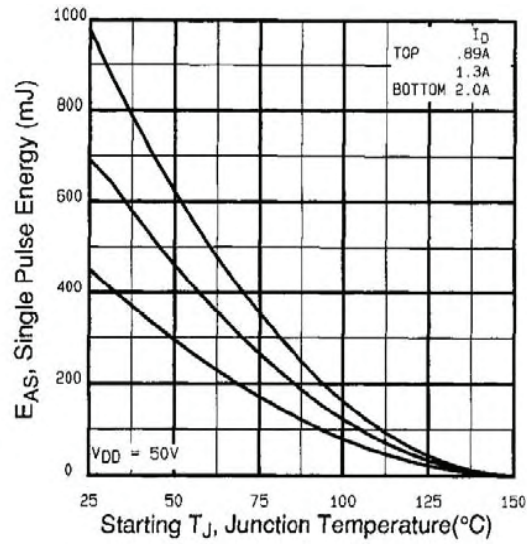


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

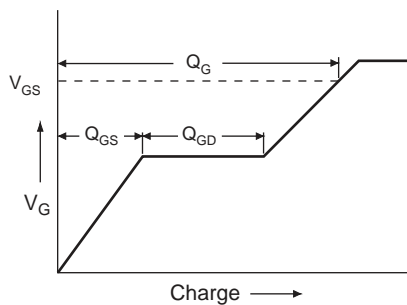


Fig. 13a - Basic Gate Charge Waveform

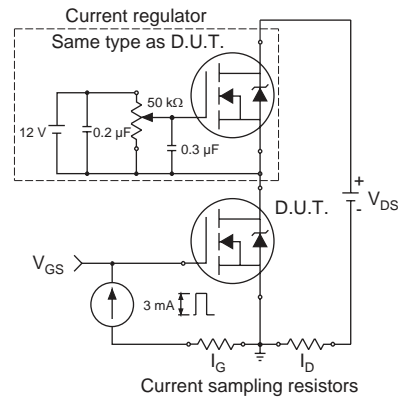
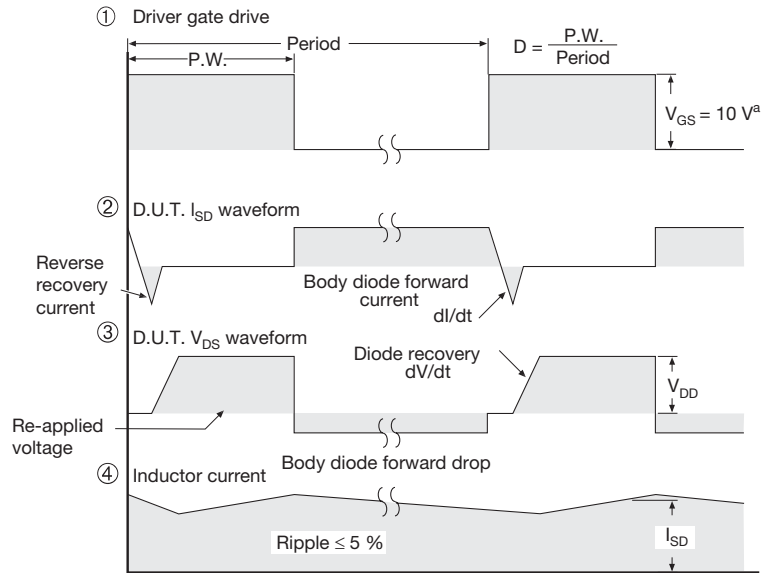
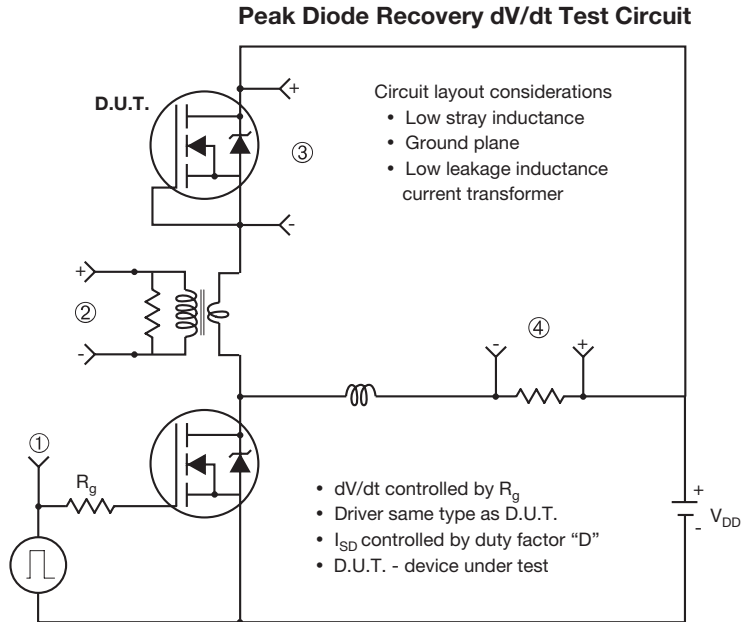


Fig. 13b - Gate Charge Test Circuit

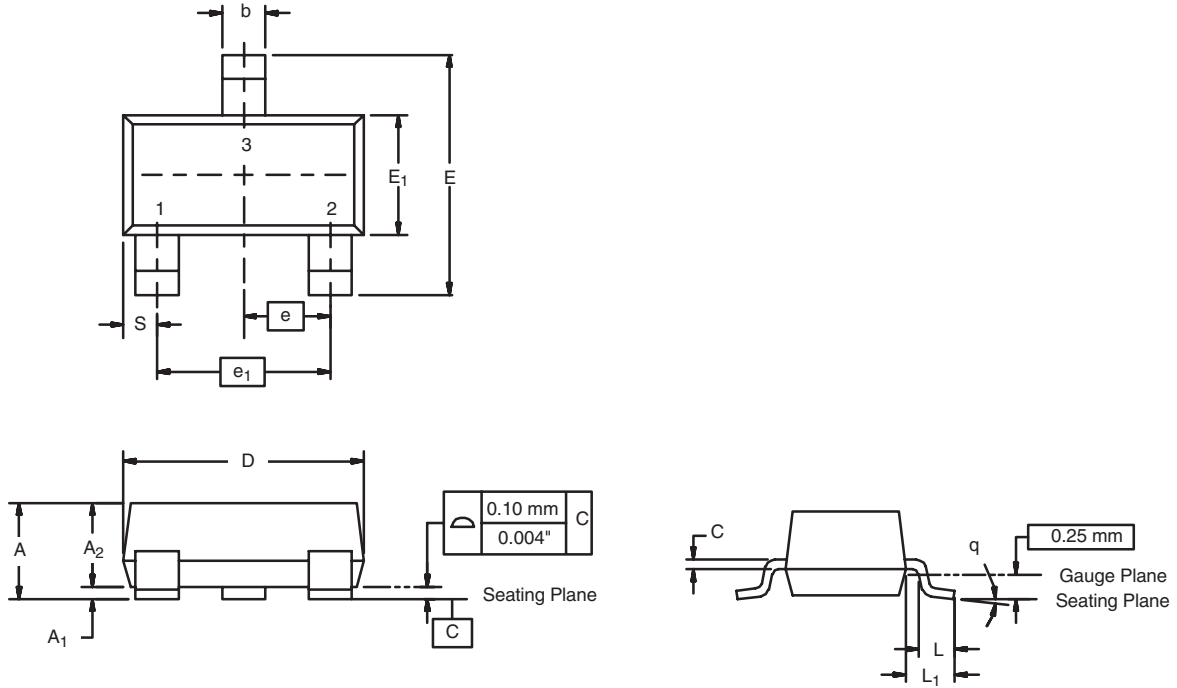


Note

a. $V_{GS} = 5 V$ for logic level devices

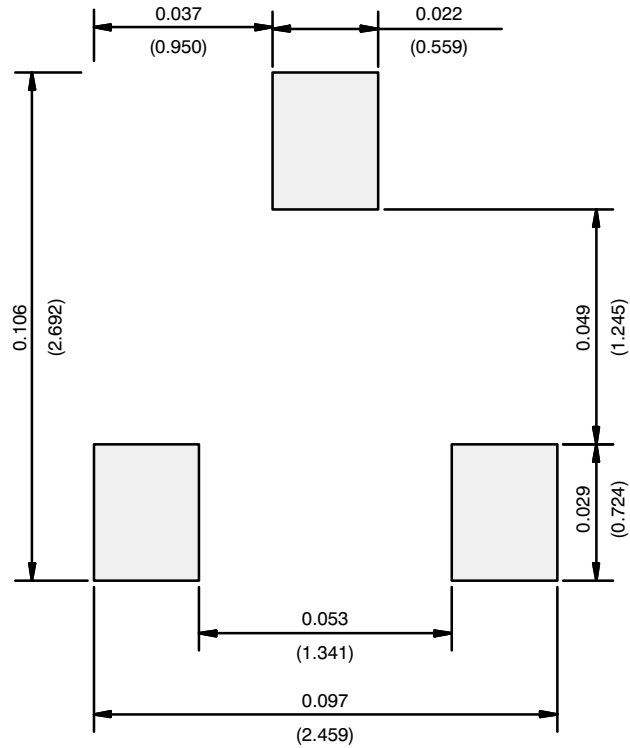
Fig. 14 - For N-Channel

SOT-23 (TO-236): 3-LEAD



| Dim | MILLIMETERS | | INCHES | |
|--------------------------------|-------------|------|------------|-------|
| | Min | Max | Min | Max |
| A | 0.89 | 1.12 | 0.035 | 0.044 |
| A ₁ | 0.01 | 0.10 | 0.0004 | 0.004 |
| A ₂ | 0.88 | 1.02 | 0.0346 | 0.040 |
| b | 0.35 | 0.50 | 0.014 | 0.020 |
| c | 0.085 | 0.18 | 0.003 | 0.007 |
| D | 2.80 | 3.04 | 0.110 | 0.120 |
| E | 2.10 | 2.64 | 0.083 | 0.104 |
| E ₁ | 1.20 | 1.40 | 0.047 | 0.055 |
| e | 0.95 BSC | | 0.0374 Ref | |
| e ₁ | 1.90 BSC | | 0.0748 Ref | |
| L | 0.40 | 0.60 | 0.016 | 0.024 |
| L ₁ | 0.64 Ref | | 0.025 Ref | |
| S | 0.50 Ref | | 0.020 Ref | |
| q | 3° | 8° | 3° | 8° |
| ECN: S-03946-Rev. K, 09-Jul-01 | | | | |
| DWG: 5479 | | | | |

RECOMMENDED MINIMUM PADS FOR SOT-23



Recommended Minimum Pads
Dimensions in Inches/(mm)

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